



Model: SAMSUNG MZ7LM1T9

S/N: S2TVNX0J104889



Disk Erasure Report

Page 1 - Erasure Status

Organisation Performing The Disk Erasure

Business Name: **Not Applicable (BN)**

Business Address: **Not Applicable (BA)**

Contact Name: **Not Applicable (BCN)**

Contact Phone: **Not Applicable (BCP)**

Customer Details

Name: **Not Applicable (CN)**

Address: **Not Applicable (CA)**

Contact Name: **Not Applicable (CCN)**

Contact Phone: **Not Applicable (CP)**

Disk Information

Make/Model: **SAMSUNG MZ7LM1T9**

Serial: **S2TVNX0J104889**

Size(Apparent): **1920 GB, 1920383410176 bytes**

Bus: **ATA-SSD**

Size(Real): **1920 GB, 1920383410176 bytes**

Disk Erasure Details

Start time: **2026/01/23 08:05:49**

End time: **2026/01/23 14:46:50**

Duration: **06:41:01**

Status: **ERASED**

Method: **PRNG Stream**

PRNG algorithm: **XORshiro256**

Final Pass(Zeros/Ones/None): **Zeros**

Verify Pass(Last/All/None): **Verify Last**

*Bytes Erased: **1920383410176, (100.00%)**

Rounds(completed/requested): **1/1**

HPA/DCO: **No hidden sectors**

HPA/DCO Size: **No hidden sectors**

Errors(pass/sync/verify): **0/0/0**

Throughput: **239 MB/sec**

Information:

*** bytes erased: The amount of drive that's been erased at least once**

Technician/Operator ID

Signature:

Name/ID: **Not Applicable (OTN)**



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```
smartctl 7.2 2020-12-30 r5155 [x86_64-linux-5.14.0-503.22.1.el9_5.x86_64] (local build)
copyright (c) 2002-20, bruce allen, christian franke, www.smartmontools.org
```

```
==== start of information section ===
model family:      Samsung based SSDs
device model:      SAMSUNG MZ7LM1T9HMJP-00005
serial number:      S2TVNX0J104889
lu wwn device id: 5 002538 c404ed2fc
firmware version:  GXT5104Q
user capacity:     1,920,383,410,176 bytes [1.92 TB]
sector size:       512 bytes logical/physical
rotation rate:     Solid State Device
form factor:       2.5 inches
trim command:      Available, deterministic, zeroed
device is:         In smartctl database [for details use: -P show]
ata version is:    ACS-2, ATA8-ACS T13/1699-D revision 4c
sata version is:   SATA 3.1, 6.0 Gb/s (current: 6.0 Gb/s)
local time is:     Fri Jan 23 14:46:52 2026 GMT
smart support is:  Available - device has SMART capability.
smart support is:  Enabled
```

```
==== start of read smart data section ===
smart overall-health self-assessment test result: PASSED
```

```
general smart values:
offline data collection status:  (0x02)Offline data collection activity
was completed without error.
auto offline data collection: Disabled.
self-test execution status:      ( 0 )The previous self-test routine completed
without error or no self-test has ever
been run.
total time to complete offline
data collection: ( 6000 ) seconds.
offline data collection
capabilities:  (0x53) SMART execute Offline immediate.
auto offline data collection on/off support.
suspend offline collection upon new
command.
no offline surface scan supported.
self-test supported.
no conveyance self-test supported.
selective self-test supported.
smart capabilities:           (0x0003)Saves SMART data before entering
power-saving mode.
supports smart auto save timer.
error logging capability:      (0x01)Error logging supported.
general purpose logging supported.
short self-test routine
recommended polling time: ( 2 ) minutes.
extended self-test routine
recommended polling time: ( 100 ) minutes.
sct capabilities:             (0x003d)SCT Status supported.
sct error recovery control supported.
sct feature control supported.
sct data table supported.
```

```
smart attributes data structure revision number: 1
vendor specific smart attributes with thresholds:
id# attribute_name      flag    value  worst  thresh  type    updated  when_failed  raw_value
  5 reallocated_sector_ct  0x0033  092    092    010    pre-fail  always   -          464
  9 power_on_hours        0x0032  086    086    000    old_age   always   -          65900
 12 power_cycle_count    0x0032  099    099    000    old_age   always   -          50
177 wear_leveling_count  0x0013  097    097    005    pre-fail   always   -          208
179 used_rsvd_blk_cnt_tot 0x0013  092    092    010    pre-fail   always   -          464
```



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180	unused_rsvd_blk_cnt_tot	0x0013	092	092	010	pre-fail	always	-	6055
181	program_fail_cnt_total	0x0032	100	100	010	old_age	always	-	0
182	erase_fail_count_total	0x0032	100	100	010	old_age	always	-	0
183	runtime_bad_block	0x0013	092	092	010	pre-fail	always	-	464
184	end-to-end_error	0x0033	100	100	097	pre-fail	always	-	0
187	uncorrectable_error_cnt	0x0032	099	099	000	old_age	always	-	223
190	airflow_temperature_cel	0x0032	061	055	000	old_age	always	-	39
194	temperature_celsius	0x0022	061	055	000	old_age	always	-	39 (min/max 20/45)
195	ecc_error_rate	0x001a	199	199	000	old_age	always	-	223
197	current_pending_sector	0x0032	100	100	000	old_age	always	-	0
199	crc_error_count	0x003e	100	100	000	old_age	always	-	0
202	exception_mode_status	0x0033	100	100	010	pre-fail	always	-	0
235	por_recovery_count	0x0012	099	099	000	old_age	always	-	43
241	total_lbbs_written	0x0032	099	099	000	old_age	always	-	465490672021
242	total_lbbs_read	0x0032	099	099	000	old_age	always	-	274417636126
243	sata_downshift_ct	0x0032	100	100	000	old_age	always	-	0
244	thermal_throttle_st	0x0032	100	100	000	old_age	always	-	0
245	timed_workld_media_wear	0x0032	100	100	000	old_age	always	-	65535
246	timed_workld_rdwr_ratio	0x0032	100	100	000	old_age	always	-	65535
247	timed_workld_timer	0x0032	100	100	000	old_age	always	-	65535
251	nand_writes	0x0032	100	100	000	old_age	always	-	895027829760

```

smart error log version: 1
ata error count: 223 (device log contains only the most recent five errors)
cr = command register [hex]
fr = features register [hex]
sc = sector count register [hex]
sn = sector number register [hex]
cl = cylinder low register [hex]
ch = cylinder high register [hex]
dh = device/head register [hex]
dc = device command register [hex]
er = error register [hex]
st = status register [hex]
powered_up_time is measured from power on, and printed as
ddd:hh:mm:ss.sss where DD=days, hh=hours, mm=minutes,
ss=sec, and sss=millisec. it "wraps" after 49.710 days.

```

```

error 223 occurred at disk power-on lifetime: 354 hours (14 days + 18 hours)
when the command that caused the error occurred, the device was active or idle.

```

```

after command completion occurred, registers were:
er st sc sn cl ch dh
-- -- -- -- -- --
00 51 01 b8 bc 37 40  error: at LBA = 0x0037bcb8 = 3652792

```

```

commands leading to the command that caused the error were:
cr fr sc sn cl ch dh dc    powered_up_time    command/feature_name
-- -- -- -- -- -- -- -- --
60 80 00 00 f9 37 40 00    1d+03:29:22.871  READ FPDMA QUEUED
60 80 00 80 f8 37 40 00    1d+03:29:22.871  READ FPDMA QUEUED
60 80 00 00 f8 37 40 00    1d+03:29:22.871  READ FPDMA QUEUED
60 80 00 80 f7 37 40 00    1d+03:29:22.871  READ FPDMA QUEUED
60 80 20 80 f6 37 40 04    1d+03:29:22.871  READ FPDMA QUEUED

```

```

error 222 occurred at disk power-on lifetime: 354 hours (14 days + 18 hours)
when the command that caused the error occurred, the device was active or idle.

```

```

after command completion occurred, registers were:
er st sc sn cl ch dh
-- -- -- -- -- --
00 51 01 10 00 00 00  error: at LBA = 0x00000010 = 16

```

```

commands leading to the command that caused the error were:

```



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```
cr fr sc sn cl ch dh dc  powered_up_time  command/feature_name
-- -- -- -- -- -- -----
60 11 00 ef bc 37 00 00  1d+03:29:22.871  READ FPDMA QUEUED
60 80 00 80 f0 37 00 00  1d+03:29:22.871  READ FPDMA QUEUED
60 80 00 00 f0 37 00 00  1d+03:29:22.871  READ FPDMA QUEUED
60 80 00 80 ef 37 00 00  1d+03:29:22.871  READ FPDMA QUEUED
60 80 00 00 ef 37 00 00  1d+03:29:22.871  READ FPDMA QUEUED
```

error 221 occurred at disk power-on lifetime: 354 hours (14 days + 18 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:
er st sc sn cl ch dh

```
-- -- -- -- -- -- -
00 51 01 10 00 00 00  error: at LBA = 0x00000010 = 16
```

commands leading to the command that caused the error were:
cr fr sc sn cl ch dh dc powered_up_time command/feature_name
-- -- -- -- -- -- -----
60 12 00 ee bc 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 00 ed 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 80 ec 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 00 ec 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 80 eb 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED

error 220 occurred at disk power-on lifetime: 354 hours (14 days + 18 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:
er st sc sn cl ch dh

```
-- -- -- -- -- -- -
00 51 01 10 00 00 00  error: at LBA = 0x00000010 = 16
```

commands leading to the command that caused the error were:
cr fr sc sn cl ch dh dc powered_up_time command/feature_name
-- -- -- -- -- -- -----
60 13 00 ed bc 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 00 e9 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 80 e8 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 00 e8 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 80 e7 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED

error 219 occurred at disk power-on lifetime: 354 hours (14 days + 18 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:
er st sc sn cl ch dh

```
-- -- -- -- -- -- -
00 51 01 10 00 00 00  error: at LBA = 0x00000010 = 16
```

commands leading to the command that caused the error were:
cr fr sc sn cl ch dh dc powered_up_time command/feature_name
-- -- -- -- -- -- -----
60 14 00 ec bc 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 80 e2 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 00 e3 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 00 80 e3 37 00 00 1d+03:29:22.871 READ FPDMA QUEUED
60 80 10 80 e5 37 00 02 1d+03:29:22.871 READ FPDMA QUEUED

smart self-test log structure revision number 1
no self-tests have been logged. [to run self-tests, use: smartctl -t]

smart selective self-test log data structure revision number 1
span min_lba max_lba current_test_status



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```
1      0      0  not_testing
2      0      0  not_testing
3      0      0  not_testing
4      0      0  not_testing
5      0      0  not_testing
255     0  65535  read_scanning was completed without error
selective self-test flags (0x0):
  after scanning selected spans, do not read-scan remainder of disk.
  if selective self-test is pending on power-up, resume after 0 minute delay.
```